

MOS FIELD EFFECT TRANSISTOR **2SJ625**

PACKAGE DRAWING (Unit: mm)

 $0.4^{+0.1}_{-0.05}$

0.95

1.9

 2.9 ± 0.2

 $0.16^{+0.1}_{-0.06}$

0 to 0.1

0.65

0.9 to 1.1

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

 2.8 ± 0.2 1.5

DESCRIPTION

The 2SJ625 is a switching device which can be driven directly by a 1.8 V power source.

This device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 1.8 V drive available
- · Low on-state resistance

 $R_{DS(on)1} = 113 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.5 \text{ V, Ip} = -1.5 \text{ A)}$

 $R_{DS(on)2} = 171 \text{ m}\Omega \text{ MAX.} (V_{GS} = -2.5 \text{ V}, I_{D} = -1.5 \text{ A})$

 $R_{DS(on)3} = 314 \text{ m}\Omega \text{ MAX.} (V_{GS} = -1.8 \text{ V}, I_{D} = -1.0 \text{ A})$

ORDERING INFORMATION

PART NUMBER	PACKAGE		
2SJ625	SC-96 (Mini Mold Thin Type)		

Marking: XM

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2SJ625	SC-96 (Mini Mold Thin Type)		

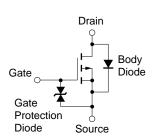
ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	-20	V
Gate to Source Voltage (Vps = 0 V)	Vgss	∓8.0	V
Drain Current (DC) (T _A = 25°C)	ID(DC)	∓3.0	Α
Drain Current (pulse) Note1	ID(pulse)	∓12	Α
Total Power Dissipation	P _{T1}	0.2	W
Total Power Dissipation Note2	P _{T2}	1.25	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

EQUIVALENT CIRCUIT

1: Gate

2 : Source 3 : Drain



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on FR-4 board, $t \le 5$ sec.

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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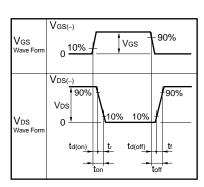


ELECTRICAL CHARACTERISTICS (TA = 25°C)

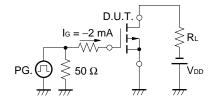
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ioss	V _{DS} = -20 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	Igss	$V_{GS} = \mp 8.0 \text{ V}, V_{DS} = 0 \text{ V}$			∓10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, \text{ ID} = -1.0 \text{ mA}$	-0.45	-0.75	-1.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -1.5 A	2.0	4.9		S
Drain to Source On-state Resistance	RDS(on)1	$V_{GS} = -4.5 \text{ V}, I_{D} = -1.5 \text{ A}$		90	113	mΩ
	RDS(on)2	Vgs = -2.5 V, ID = -1.5 A		128	171	mΩ
	RDS(on)3	V _{GS} = -1.8 V, I _D = -1.0 A		188	314	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		348		pF
Output Capacitance	Coss	V _{GS} = 0 V		88		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		38		pF
Turn-on Delay Time	td(on)	V _{DD} = -10 V, I _D = -1.5 A		39		ns
Rise Time	t r	V _{GS} = -4.0 V		190		ns
Turn-off Delay Time	t _{d(off)}	$R_G = 10 \Omega$		220		ns
Fall Time	t f			250		ns
Total Gate Charge	Q _G	V _{DD} = -16 V		2.6		nC
Gate to Source Charge	Qgs	Vgs = -4.0 V		0.8		nC
Gate to Drain Charge	Q _{GD}	lb = -3.0 A		0.9		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 3.0 A, VGS = 0 V		0.89		V

TEST CIRCUIT 1 SWITCHING TIME

PG. R_{G} $\tau = 1 \mu s$ Duty Cycle $\leq 1\%$

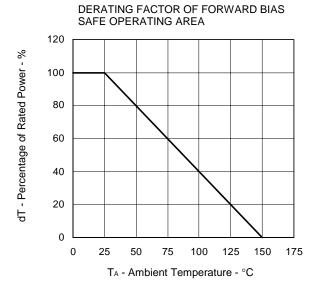


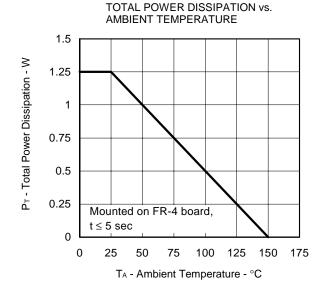
TEST CIRCUIT 2 GATE CHARGE



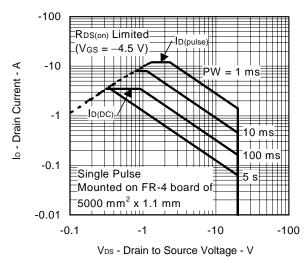


TYPICAL CHARACTERISTICS (TA = 25°C)

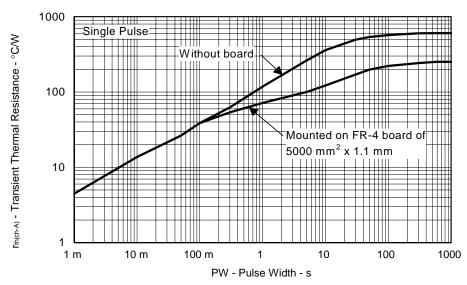




FORWARD BIAS SAFE OPERATING AREA

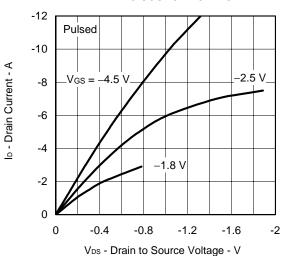


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

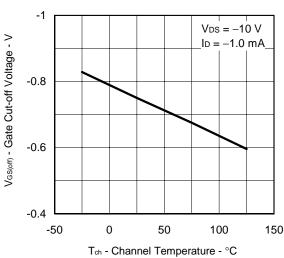


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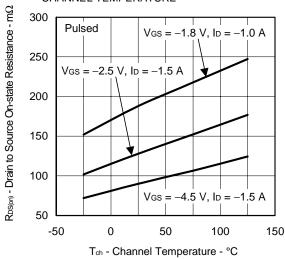
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



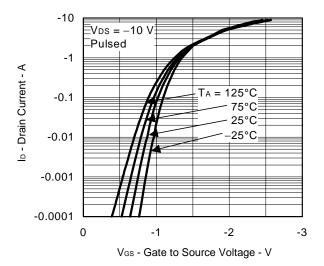
GATE CUT-OFF VOLTAGE vs. CHANNEL TEMPERATURE



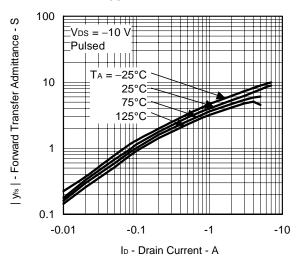
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



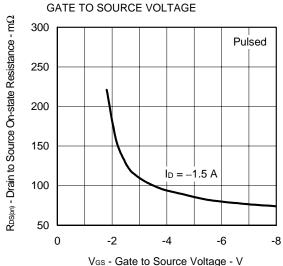
FORWARD TRANSFER CHARACTERISTICS



FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

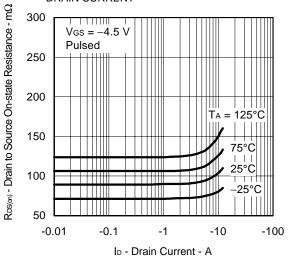


DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

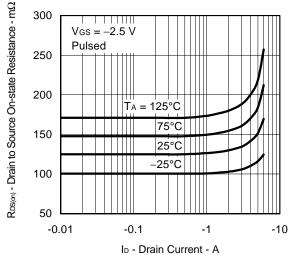




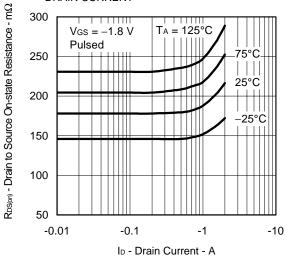
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



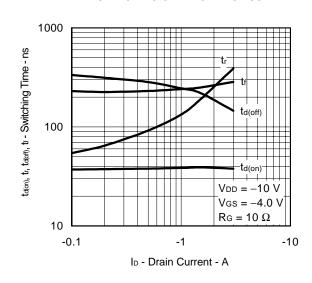
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



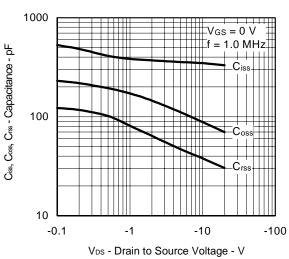
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



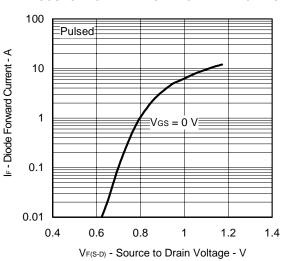
SWITCHING CHARACTERISTICS



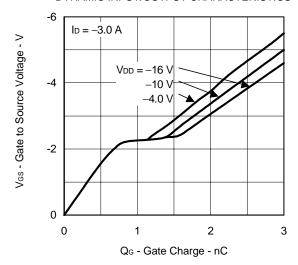
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT/OUTPUT CHARACTERISTICS



[MEMO]

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